

Search Notes

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

SHIGENO ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
347	29,30	5/25/2005	SWH
347	32,33	5/25/2005	SWH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR